

Defect Detect

Low Cost Quality Control Solution at the Edge



Team



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Data Synthesis and
Software Flow



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Machine Learning



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Hardware Design

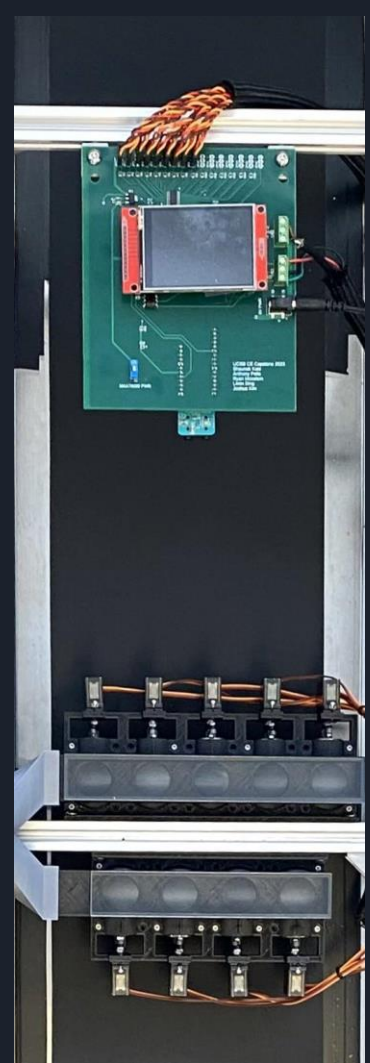
Motivation

- Current anomaly removal systems on the market are either expensive and inefficient or highly specialized
- Replace legacy embedded microcontroller solutions with similar cost AI powered systems

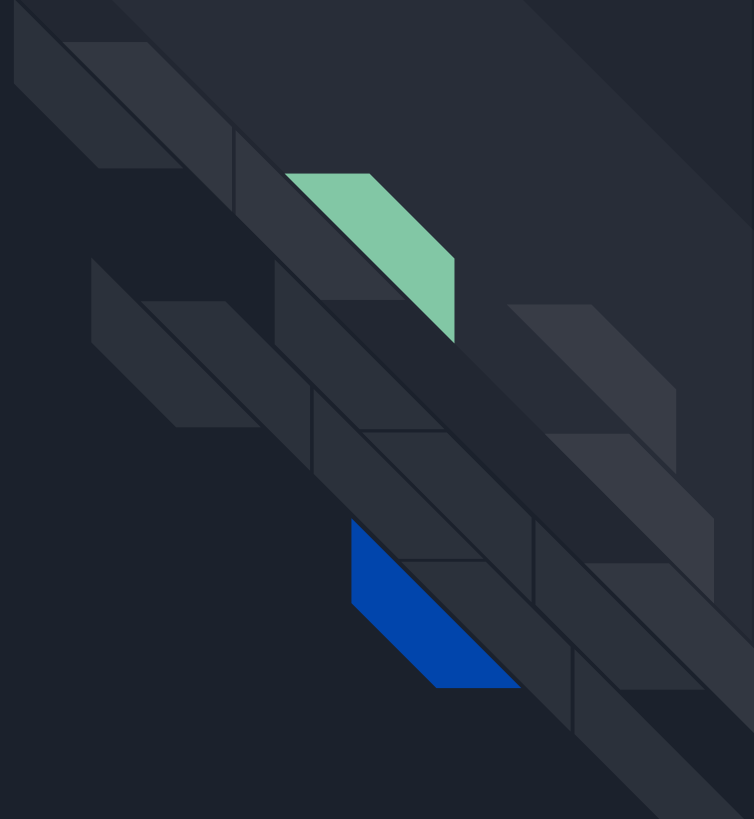


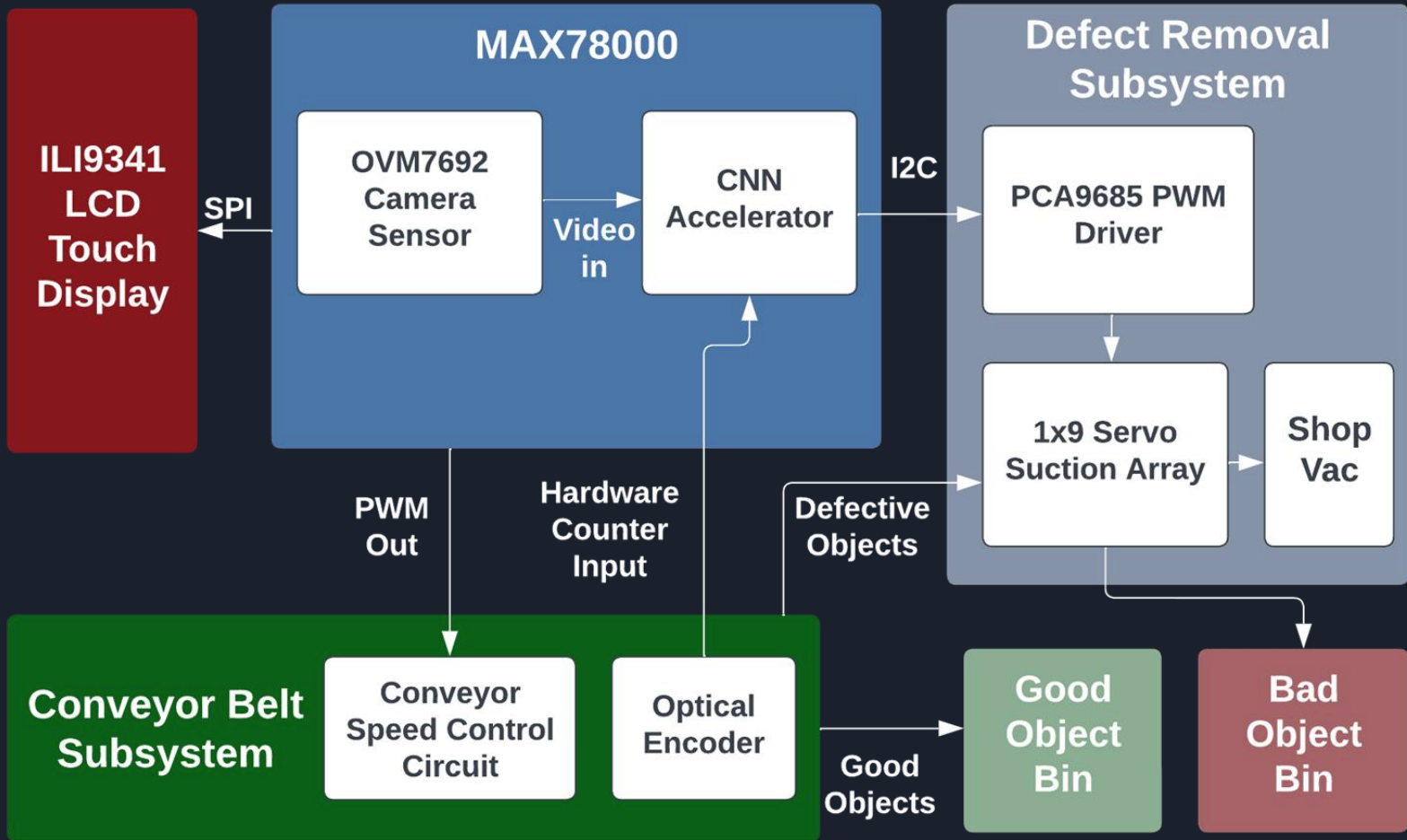
System Overview

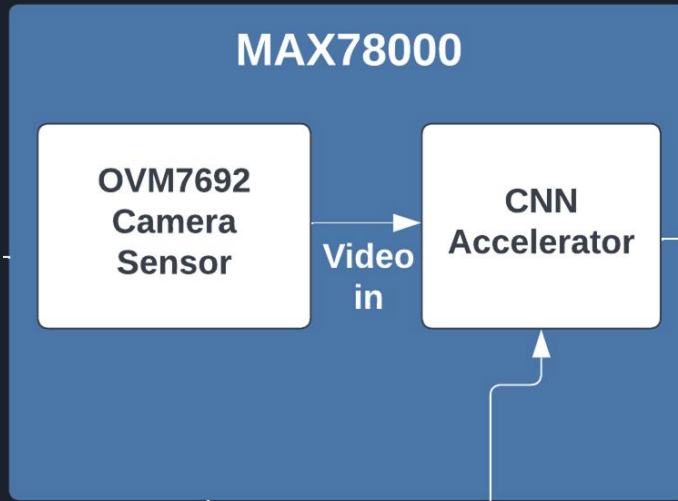
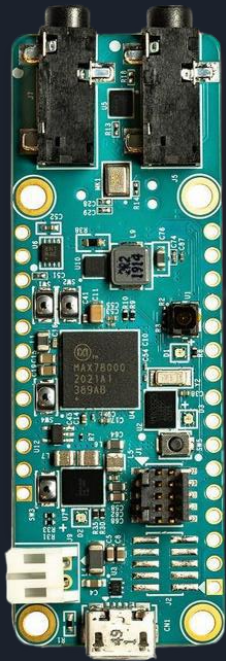
- Unfiltered pinto beans are placed on a conveyor belt
- Custom CNN Model detects defective objects
- Vacuum system removes defects further down the conveyor belt



Block Diagram







MAX78000 Featherboard

- Development Board with MAX78000 AI Microcontroller and VGA Camera Module
- Runs CNN Model and removal mechanism logic
- Streams frames and detections to LCD Display

MAX78000 SPECS

Internal SRAM	128 KB
Core	ARM Cortex-M4F
Internal Flash	512 KB
Clock Max Speed	100 Mhz



Defect Removal Subsystem

- Nine vacuum channels span the width of the belt
- I2C interfaced PWM driver operates servo-controlled ball valves
- Defective objects are sucked into the bad object bin

Defect Removal Subsystem

PCA9685 PWM Driver

1x9 Servo Suction Array

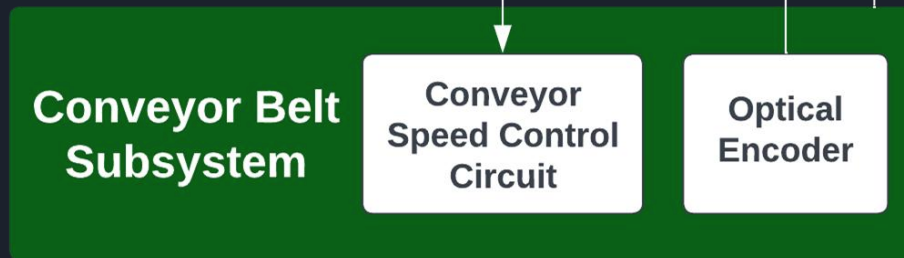
Shop Vac

Good Object Bin

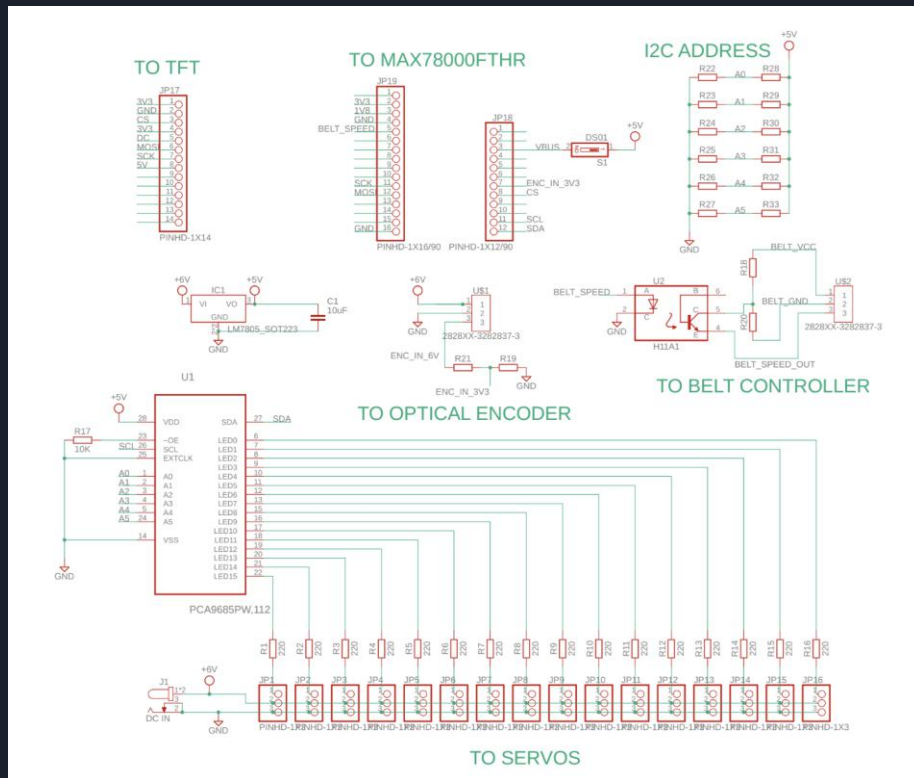
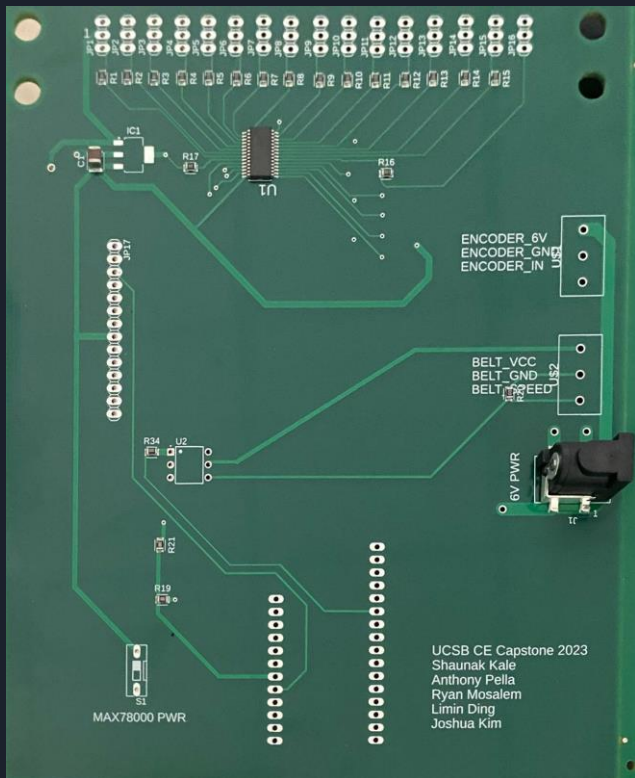
Bad Object Bin

Conveyor Belt Subsystem

- PWM connection to conveyor belt circuitry allows for accurate speed control
- Optical encoder connected to MAX78000 hardware counter provides accurate position



Custom PCB



Embedded Software Flow

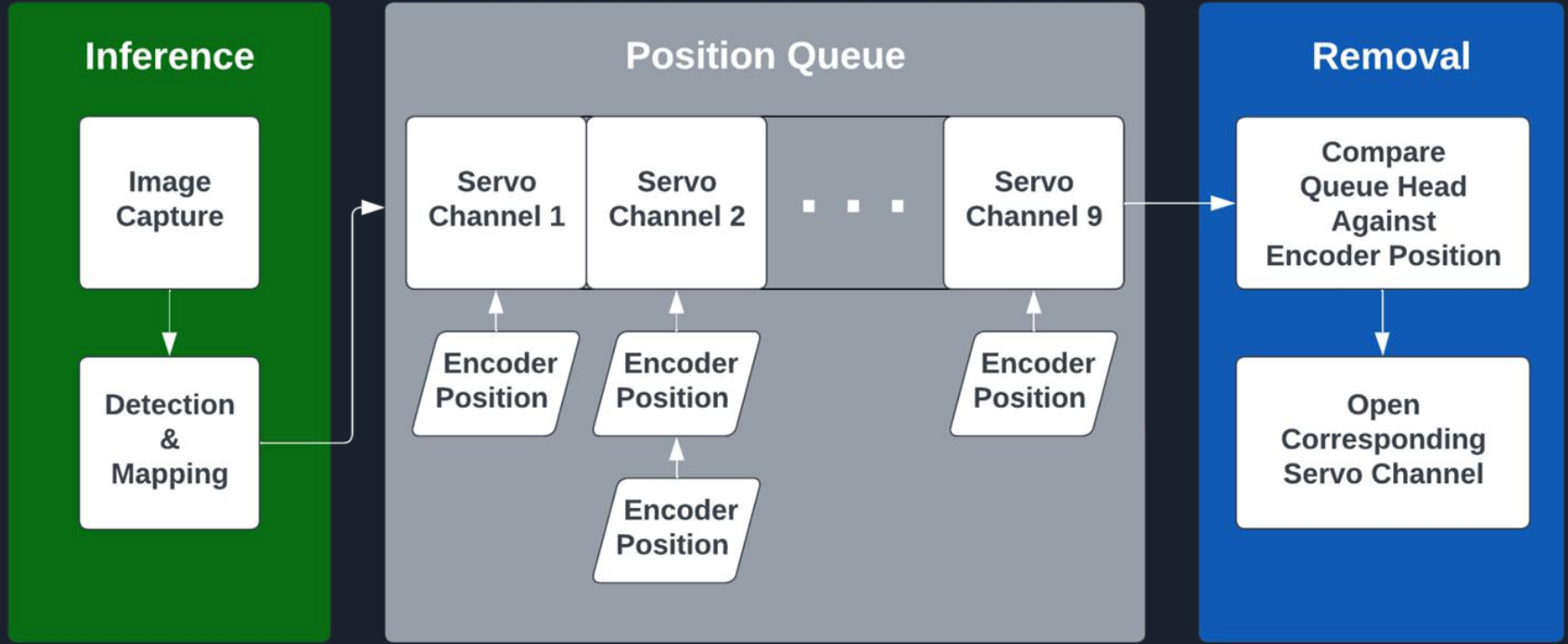
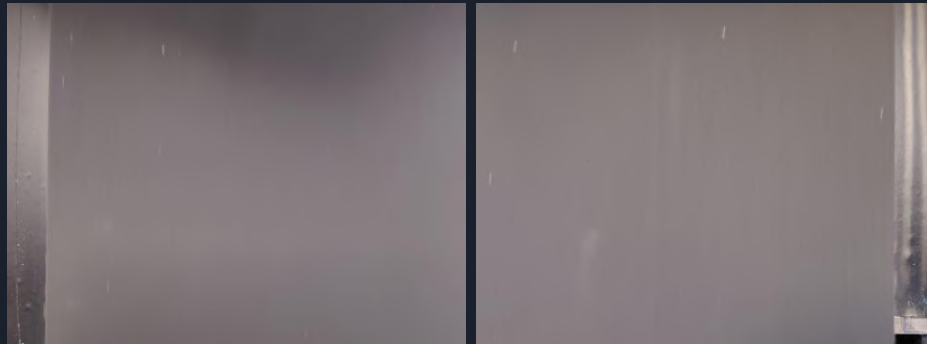


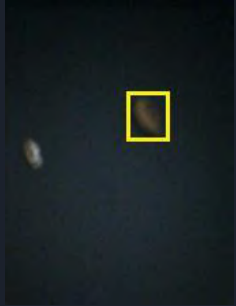
Image Capture

- Input size for CNN model: 224 x 168
- One image can only cover half of the conveyor belt
 - Use two images to cover the whole width of conveyor belt
 - Only store one image to save memory

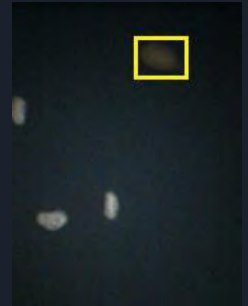
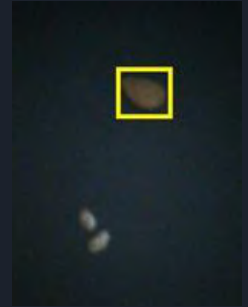




Machine Learning Development Process

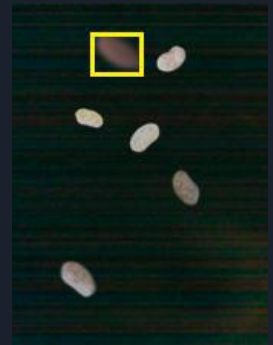
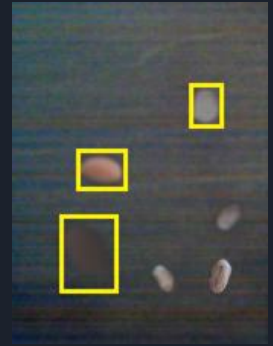


- Generate artificial data
- Train classification model using PyTorch to detect defects and ignore non-defects as the background
- Quantization and synthesis of model
- Test on MAX78000 and repeat the process

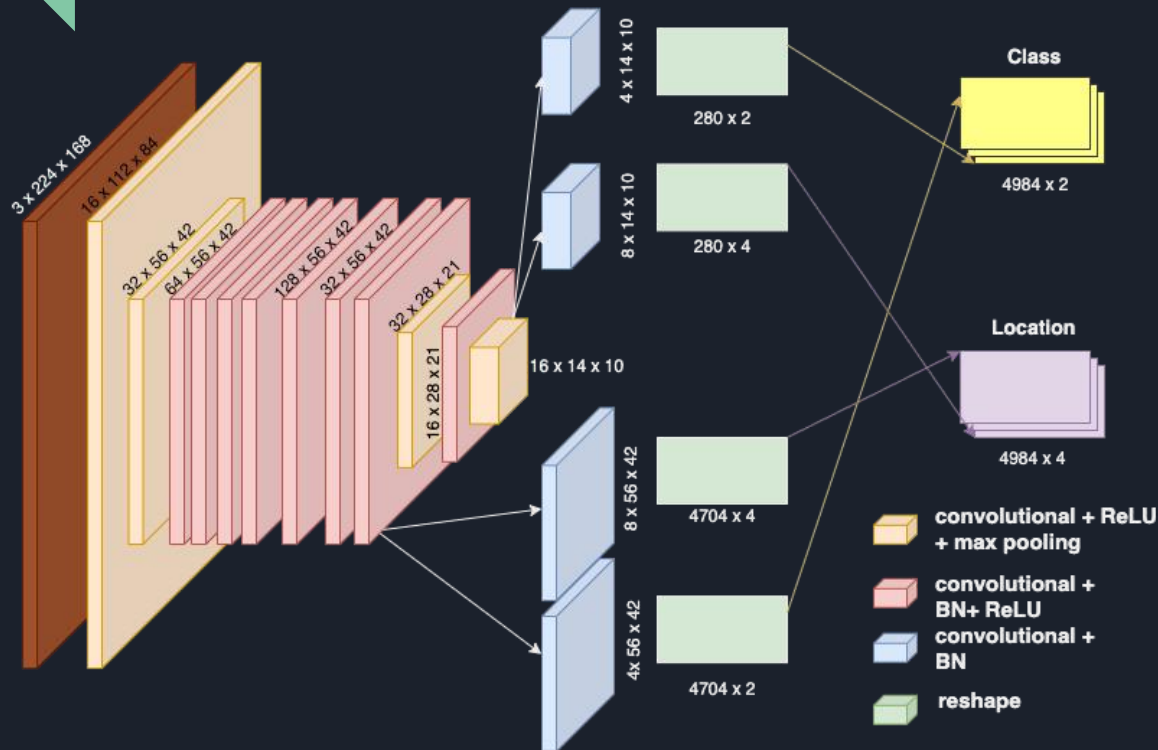


Data Synthesis

- Uses OpenCV for object processing and creation
- Captured hundreds of camera images and used contour detection to crop out individual objects
- Composited objects on varying backgrounds + Random background + Automatic annotation
- Fast prototyping and model building



CNN Architecture



- Weight memory: 260,568 bytes out of 442,368 bytes (58.9%)
- Inference Time: 49.9 ms
- 16 convolutional layers

Challenges

- Sensitivity to external light
- Can only capture 3 frames per second
- Multiple removal system hardware redesigns
- Data collection and annotation
- Creating realistic synthetic images



Good
Bin

Defect
Bin

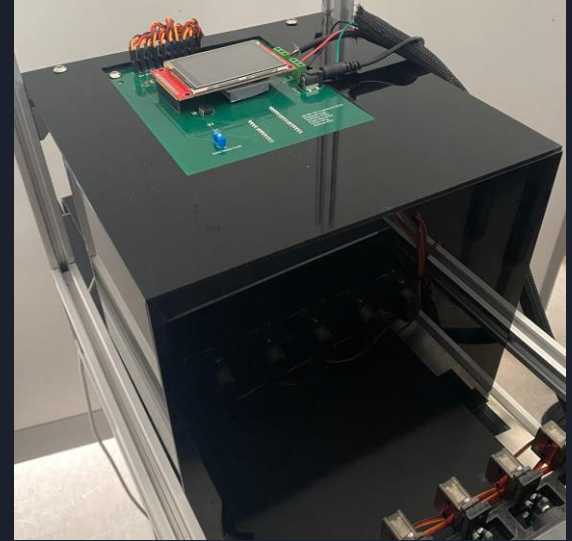


Synthetic

Real

Improvements

- Enclosure to control for external light
- Manually set sensor gain & exposure time
- Increased the frames per second from ~3 to ~7 by enabling camera sleeping between frames and using DMA to transfer images to the TFT display
- Train ~100 epochs with dataset size of 40000+ images
 - Mean Average Precision: 0.93
- Fine tuned compositing algorithm and added sparsity constraint for synthetic images
- Created a highly accurate model, suitable for industrial settings



Results

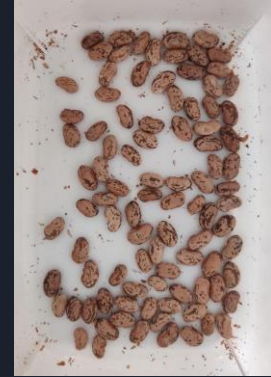
Good Bin



April



May



June

Defect Bin







Acknowledgements

- A special thanks to
 - Dr. Yogananda Isukapalli - Capstone Instructor
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Questions?

